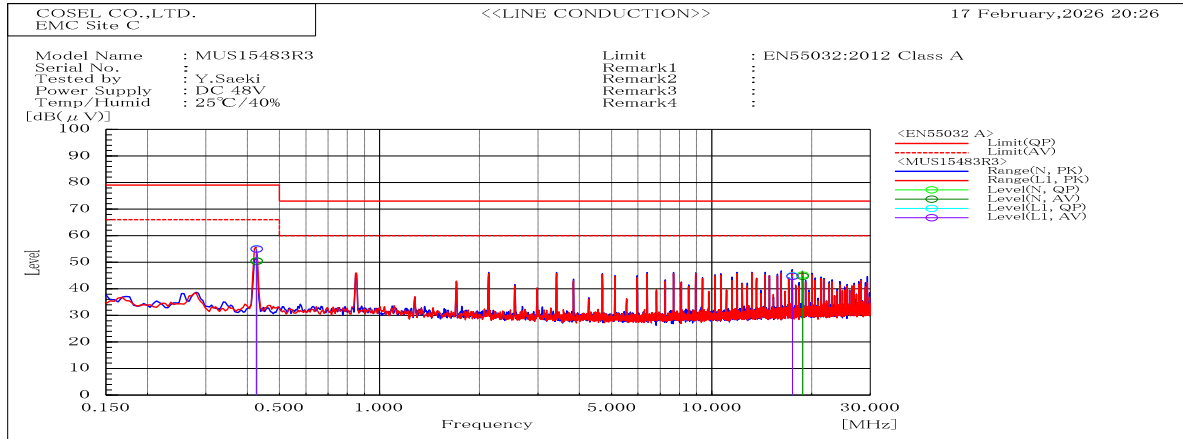
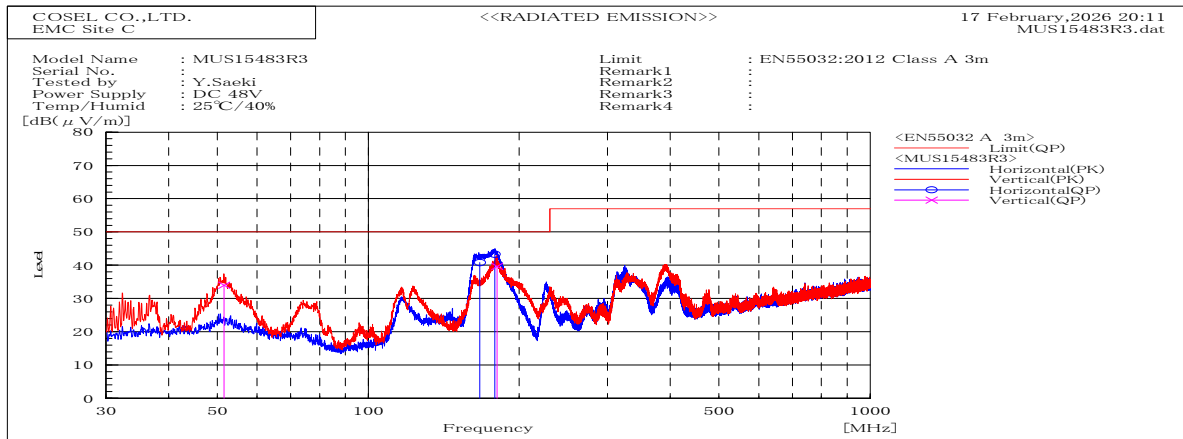


DATA SHEET

Model	MUS15483R3	Date	15-May-26
Test	EMI	Temp.	25 degreeC
	Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	Y.Saeki



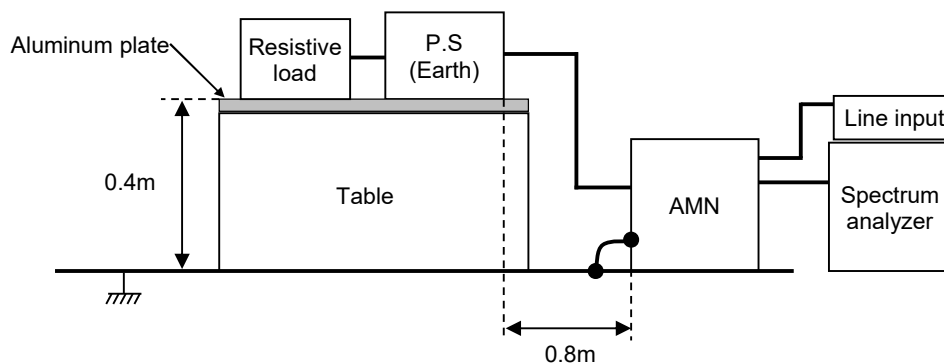
Frequency	Line	Level	Limit	Margin	Pass/Fail	Remark
MHz		dB(μV)	dB(μV)	dB		
		QP	AV	QP	AV	
0.427	N	50.5	50.4	79	66	28.5
18.777	N	45.3	44.8	73	60	27.7
0.427	L1	55.1	55	79	66	23.9
17.495	L1	45	44.7	73	60	28



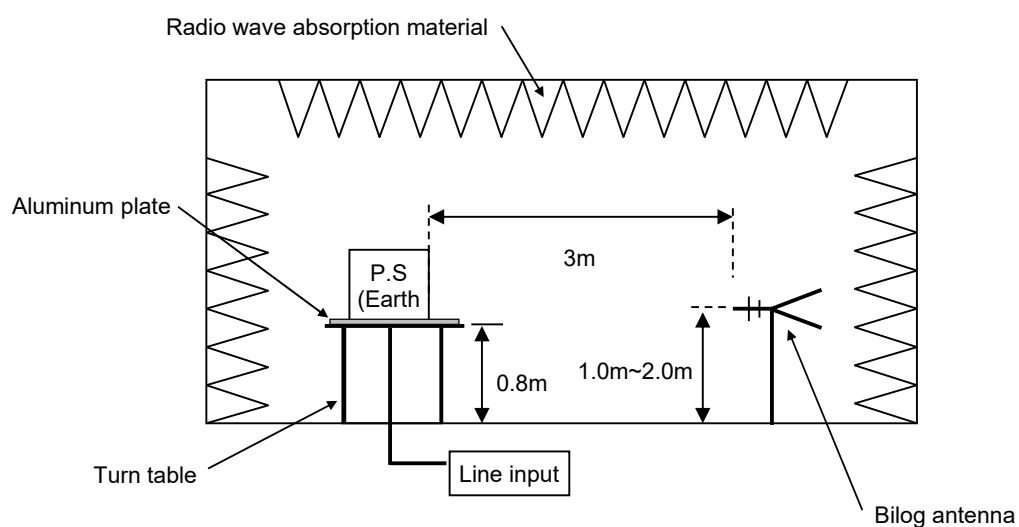
Frequency	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height	Angle	Remark
MHz			dB(μV/m)	dB(μV/m)	dB		cm	deg	
			QP	QP	QP				
166.883	H	Stable	40.8	50	9.2	Pass	174.8	188.1	
178.572	H	Stable	43.3	50	6.7	Pass	200	3.6	
51.592	V	Stable	34	50	16	Pass	100.2	229.9	
180.625	V	Stable	39.7	50	10.3	Pass	100.2	230	

DATA SHEET		Date	15-May-26
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	Y.Saeki

1. Line conduction



2. Radiated emission



Conditions

Test : EMI
Model Name: MUS15□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

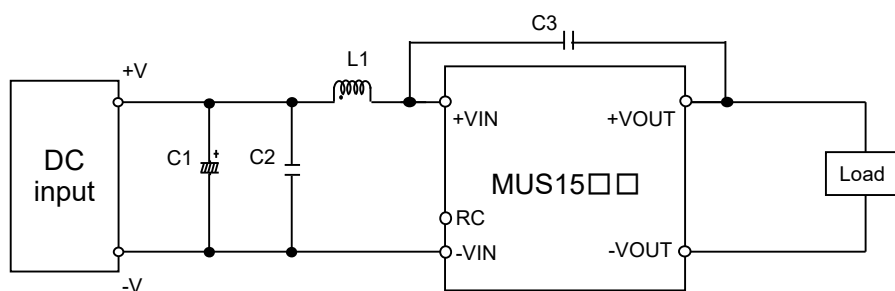


Fig.1 MUS15□□ Testing circuitry

C1 :	MUS1524□	50V 47 μ F Electric capacitor (UPWseries NICHICON)
	MUS1548□	-
C2 :	MUS1524□	50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MUS1548□	100V 2.2 μ F Ceramic capacitor (C3216X7S2A225KT TDK)
C3 :	MUS15□□	2000V 1000pF Ceramic capacitor (C3225X7S3D102K200AA TDK)
L1 :	MUS1524□	1600mA 22 μ H Inductor (LQH5BPN220M38 MURATA MANUFACTURING)
	MUS1548□	1100mA 47 μ H Inductor (LQH5BPN470M38 MURATA MANUFACTURING)